



A Concise Introduction to Random Number Generation

Peter Hellekalek

Dept. of Mathematics, University of Salzburg



Overview of This Talk

How to assess RNGs?

- ▶ criteria
- ▶ a checklist



Overview of This Talk

How to assess RNGs?

- ▶ criteria
- ▶ a checklist

A note on statistical testing

- ▶ strategies
- ▶ Maurer's Universal Test and related tests



Overview of This Talk

How to assess RNGs?

- ▶ criteria
- ▶ a checklist

A note on statistical testing

- ▶ strategies
- ▶ Maurer's Universal Test and related tests

Interesting RNGs

- ▶ AES
- ▶ HAVEG(E)



RNGs: The Goal

What we want . . .

A device (hardware or software) whose output is random.



RNGs: The Goal

What we want ...

A device (hardware or software) whose output is random.

More precisely ...

Want to generate bits (or numbers) that **appear** like being sampled from a uniform distribution on $\{0, 1\}$ (or $[0, 1[$), independently of each other.



RNGs: The Reality

What we get...

Finite output streams that pass many [tests of randomness](#).



RNGs: The Reality

What we get...

Finite output streams that pass many **tests of randomness**.

Pseudorandom number generator (PRNG)

Deterministic algorithm whose output **mimics** finite random sequences.



RNGs: The Reality

What we get...

Finite output streams that pass many **tests of randomness**.

Pseudorandom number generator (PRNG)

Deterministic algorithm whose output **mimics** finite random sequences.

Question

What are **random sequences**?



Randomness

Quote

"A finite sequence is random if there is no short sequence that describes it fully, in some unambiguous mathematical notation."

... A. Kolmogoroff

Quote

"A string is random if it cannot be algorithmically compressed."

... C. Calude

Remark

The basic idea of Kolmogoroff complexity:

Randomness = Incompressibility



RNGs: Practice

Quote

*“Monte Carlo results are misleading when **correlations** hidden in the random numbers and in the simulated system **interfere constructively**.”*

... A. Compagner, Phys. Rev. E **52**(1995)

Quote

*“**Ironically**, pseudorandom numbers often appear to be **more random** than random numbers obtained from physical sources.”*

... A. Rukhin et al., NIST Special Publ. 800-22

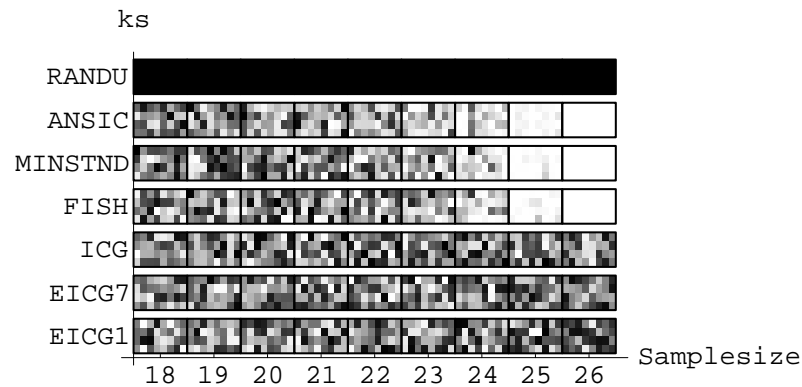


RNGs: An Illustration

With RNGs, there are **no guarantees**.

RNGs: An Illustration

With RNGs, there are **no guarantees**.



True Value: Irregular Pattern in Every Box

RNGs: LCGs and (E)ICGs

Sample Size: $2^{18} \dots 2^{26}$



Phenomena

Setup

- ▶ RNG: LCG(2^{31} , 65539, 0, 1), i.e. RANDU



Phenomena

Setup

- ▶ RNG: LCG(2^{31} , 65539, 0, 1), i.e. RANDU
- ▶ Dimension: $d = 2, 3$



Phenomena

Setup

- ▶ RNG: LCG(2^{31} , 65539, 0, 1), i.e. RANDU
- ▶ Dimension: $d = 2, 3$
- ▶ Sample size: $N = 2^{16}$



Phenomena

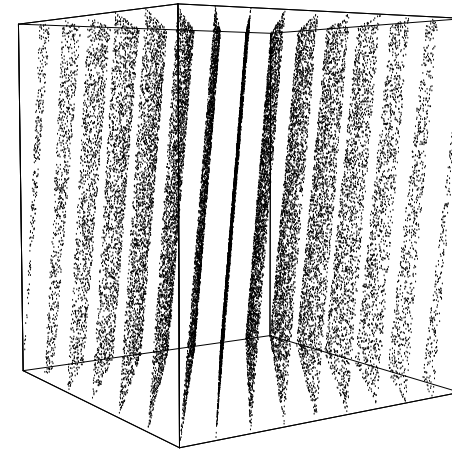
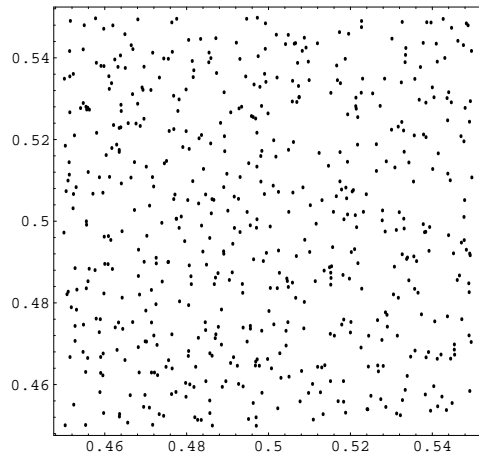
Setup

- ▶ RNG: LCG(2^{31} , 65539, 0, 1), i.e. RANDU
- ▶ Dimension: $d = 2, 3$
- ▶ Sample size: $N = 2^{16}$
- ▶ Plot nonoverlapping pairs (x_{2n}, x_{2n+1}) and triples $(x_{3n}, x_{3n+1}, x_{3n+2})$, $0 \leq n < N$.



Phenomena: Increasing the Dimension

We increase the dimension from $d = 2$ to $d = 3$:



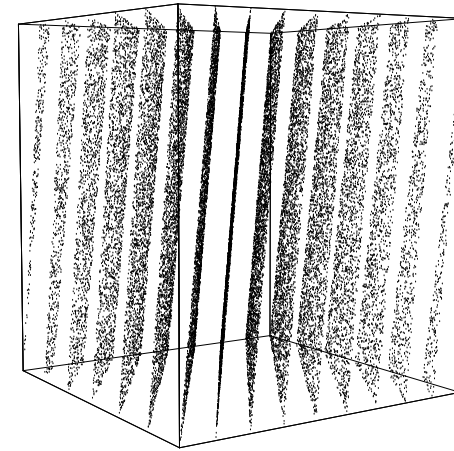
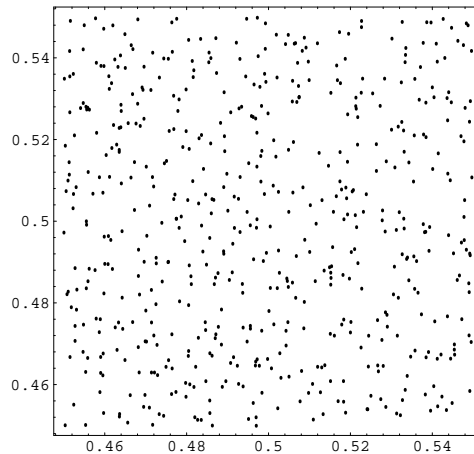
Question

How to prevent such **unpleasant surprises**?



Phenomena: Increasing the Dimension

We increase the dimension from $d = 2$ to $d = 3$:



Question

How to prevent such **unpleasant surprises**?

Answer

Theoretical correlation analysis and/or statistical testing.



Linear Congruential Generator (LCG)

Parameters

▶ m ... modulus



Linear Congruential Generator (LCG)

Parameters

▶ m ... modulus

▶ a ... multiplier



Linear Congruential Generator (LCG)

Parameters

- ▶ m ... modulus
- ▶ a ... multiplier
- ▶ b ... additive constant



Linear Congruential Generator (LCG)

Parameters

- ▶ m ... modulus
- ▶ a ... multiplier
- ▶ b ... additive constant
- ▶ y_0 ... initial value



Linear Congruential Generator (LCG)

Parameters

- ▶ m ... modulus
- ▶ a ... multiplier
- ▶ b ... additive constant
- ▶ y_0 ... initial value

Defining congruence

$$y_{n+1} \equiv a \cdot y_n + b \pmod{m}, \quad n \geq 0$$

... LCG(m, a, b, y_0)



Linear Congruential Generator (LCG)

Parameters

- ▶ m ... modulus
- ▶ a ... multiplier
- ▶ b ... additive constant
- ▶ y_0 ... initial value

Defining congruence

$$y_{n+1} \equiv a \cdot y_n + b \pmod{m}, \quad n \geq 0$$

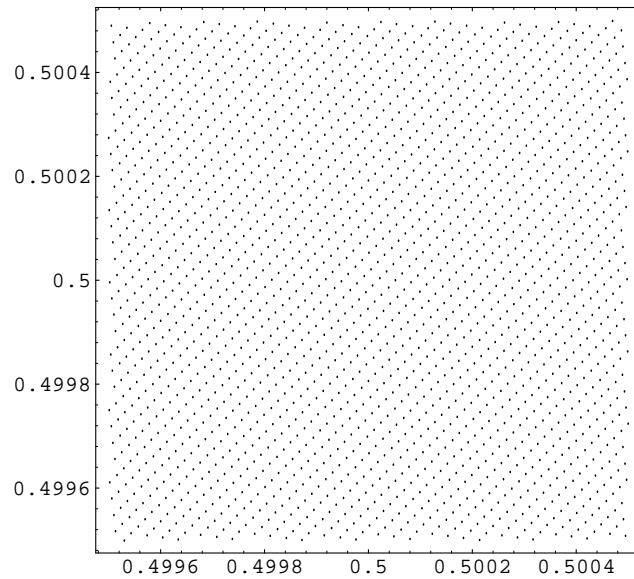
... LCG(m, a, b, y_0)

Output stream

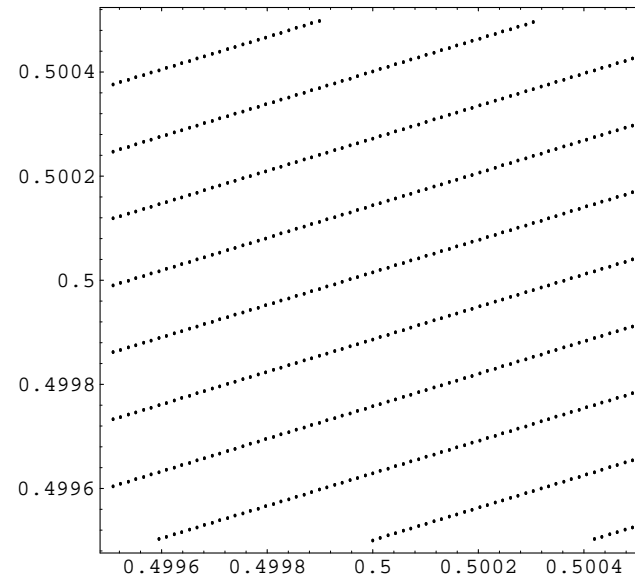
$$x_n := \frac{y_n}{m} \in [0, 1[, \quad n = 0, 1, \dots$$



LCGs: Two Examples



LCG($2^{31} - 1, 630360016, 0, 1$)



LCG($2^{32}, 69069, 0, 1$)



Inversive Congruential Generator (ICG)

Parameters

- ▶ m ... modulus (usually a big prime)



Inversive Congruential Generator (ICG)

Parameters

- ▶ m ... modulus (usually a big prime)
- ▶ a ... multiplier



Inversive Congruential Generator (ICG)

Parameters

- ▶ m ... modulus (usually a big prime)
- ▶ a ... multiplier
- ▶ b ... additive constant



Inversive Congruential Generator (ICG)

Parameters

- ▶ m ... modulus (usually a big prime)
- ▶ a ... multiplier
- ▶ b ... additive constant
- ▶ y_0 ... initial value



Inversive Congruential Generator (ICG)

Parameters

- ▶ m ... modulus (usually a big prime)
- ▶ a ... multiplier
- ▶ b ... additive constant
- ▶ y_0 ... initial value

Defining congruence

$$y_{n+1} \equiv a \cdot \overline{y_n} + b \pmod{m}, \quad n \geq 0$$

($\overline{c} = c^{-1}$ for $c \neq 0$, $\overline{c} = 0$ if $c = 0$.)

... ICG(m, a, b, y_0)



Inversive Congruential Generator (ICG)

Parameters

- ▶ m ... modulus (usually a big prime)
- ▶ a ... multiplier
- ▶ b ... additive constant
- ▶ y_0 ... initial value

Defining congruence

$$y_{n+1} \equiv a \cdot \bar{y}_n + b \pmod{m}, \quad n \geq 0$$

($\bar{c} = c^{-1}$ for $c \neq 0$, $\bar{c} = 0$ if $c = 0$.)

... ICG(m, a, b, y_0)

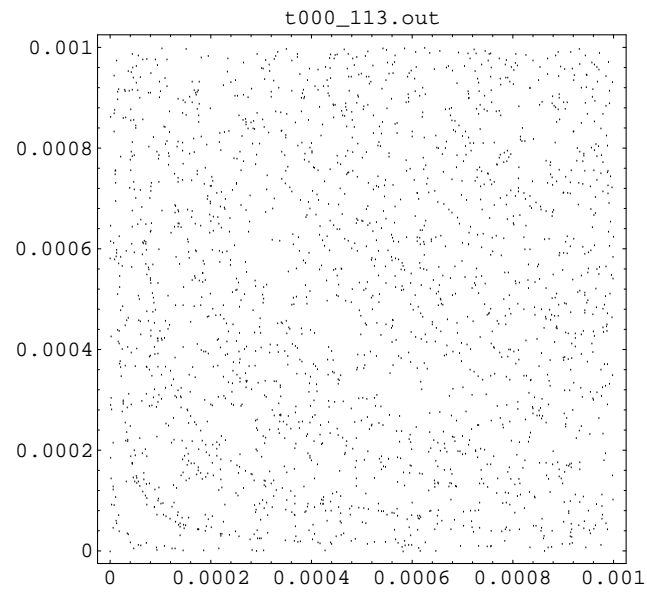
Output stream

$$x_n := \frac{y_n}{m} \in [0, 1[, \quad n = 0, 1, \dots$$

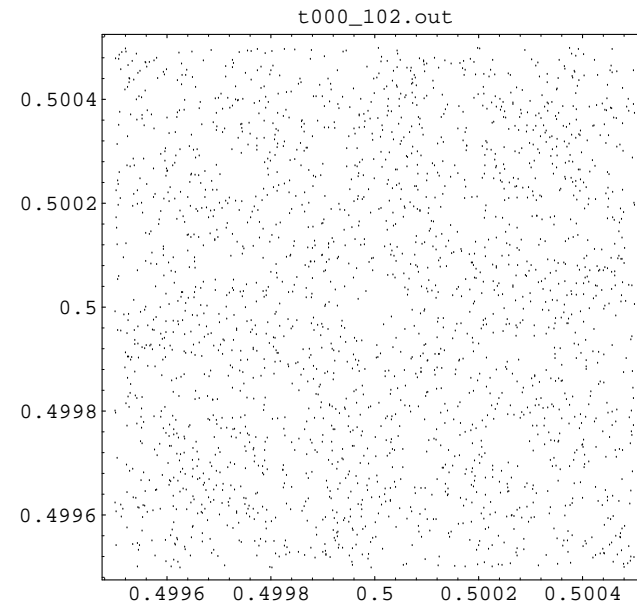


ICG: Point Structure

ICG($2^{31} - 1, 1288490188, 1, 1$)



lower left corner



middle section



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,
- ▶ \mathcal{I} is the input space,



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,
- ▶ \mathcal{I} is the input space,
- ▶ $T : \mathcal{I} \times \mathcal{S} \rightarrow \mathcal{S}$ is the transition function,



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,
- ▶ \mathcal{I} is the input space,
- ▶ $T : \mathcal{I} \times \mathcal{S} \rightarrow \mathcal{S}$ is the transition function,
- ▶ \mathcal{O} is the finite output space,



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,
- ▶ \mathcal{I} is the input space,
- ▶ $T : \mathcal{I} \times \mathcal{S} \rightarrow \mathcal{S}$ is the transition function,
- ▶ \mathcal{O} is the finite output space,
- ▶ $g : \mathcal{S} \rightarrow \mathcal{O}$ is the output function,



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,
- ▶ \mathcal{I} is the input space,
- ▶ $T : \mathcal{I} \times \mathcal{S} \rightarrow \mathcal{S}$ is the transition function,
- ▶ \mathcal{O} is the finite output space,
- ▶ $g : \mathcal{S} \rightarrow \mathcal{O}$ is the output function,
- ▶ $s_0 \in \mathcal{S}$ is the seed.



Pseudorandom Number Generators (PRNGs)

PRNG: A tuple $G = (\mathcal{S}, \mathcal{I}, T, \mathcal{O}, g, s_0)$, where

- ▶ \mathcal{S} is the finite state space,
- ▶ \mathcal{I} is the input space,
- ▶ $T : \mathcal{I} \times \mathcal{S} \rightarrow \mathcal{S}$ is the transition function,
- ▶ \mathcal{O} is the finite output space,
- ▶ $g : \mathcal{S} \rightarrow \mathcal{O}$ is the output function,
- ▶ $s_0 \in \mathcal{S}$ is the seed.

The **next state** s_{n+1} is generated by

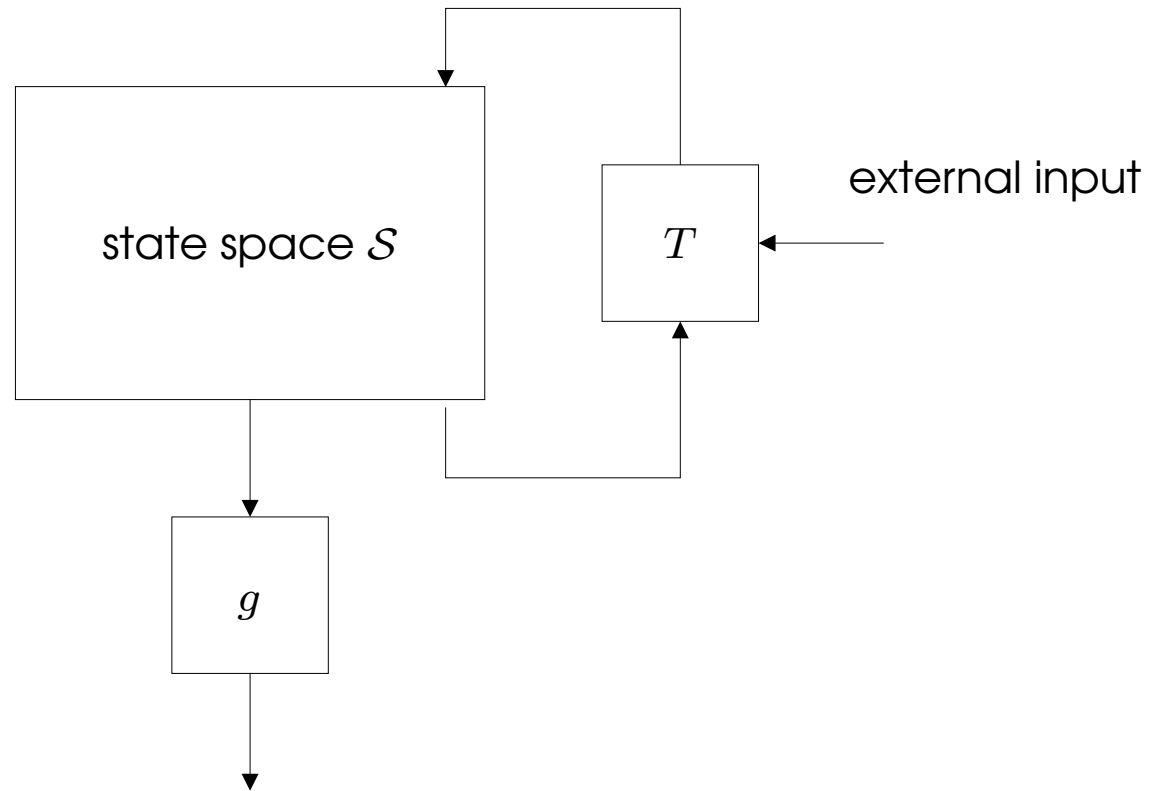
$$s_{n+1} = T(i_n, s_n), \quad n \geq 0,$$

the **output stream** $(o_n)_{n \geq 0}$ is computed by

$$o_n = g(s_n), \quad n \geq 0.$$



PRNGs: The Structure



The Structure of a PRNG



Classification of RNGs

Types of RNGs

| Type of Application | |
|-----------------------------|----------------------------------|
| Simulation (Monte Carlo) | Cryptography (stream ciphers) |



Classification of RNGs

Types of RNGs

| Type of Application | |
|-----------------------------|----------------------------------|
| Simulation (Monte Carlo) | Cryptography (stream ciphers) |

| Type of Platform | |
|-------------------------------------|---------------------------------|
| Hardware ("physical" randomness) | Software (pseudo-randomness) |



Classification of RNGs

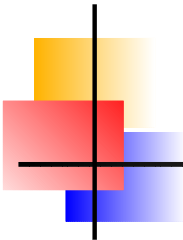
Types of RNGs

| Type of Application | |
|-----------------------------|----------------------------------|
| Simulation (Monte Carlo) | Cryptography (stream ciphers) |

| Type of Platform | |
|-------------------------------------|---------------------------------|
| Hardware ("physical" randomness) | Software (pseudo-randomness) |

Classes of PRNGs

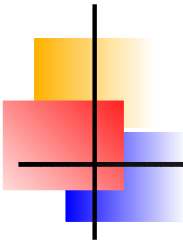
| PRNGs: Type of Algorithm | |
|---------------------------------|-----------|
| linear | nonlinear |



Which RNG?

RNG vs. Application

| RNG \ Application | Simulation | Cryptography |
|-------------------|-----------------|----------------|
| Hardware | not recommended | task dependent |
| Software | recommended | task dependent |



Which RNG?

RNG vs. Application

| RNG \ Application | Simulation | Cryptography |
|-------------------|-----------------|----------------|
| Hardware | not recommended | task dependent |
| Software | recommended | task dependent |

PRNG vs. Application

| PRNG \ Application | Simulation | Cryptography |
|--------------------|---|-------------------------------------|
| Linear | recommended (if chosen properly) | not recommended (insecure) |
| Nonlinear | task dependent (too small, too slow) | recommended (if chosen properly) |



Checklist: Theoretical Support

| | | |
|-------------------------------|--------------------------------|--|
| A) Theoretical Support | | |
| Period Length | Conditions | |
| | Algorithms for parameters | |
| Structural Properties | Intrinsic structures | |
| | Equidistribution properties | |
| | Predictability | |
| Correlation Analysis | For particular parameters | |
| | For particular initializations | |
| | For parts of the period | |
| | For subsequences | |
| | For combinations of RNGs | |



Checklist: Statistical Testing

B) Statistical Testing

Variable sample size

Two- or higher level tests

| | |
|-------------------------------------|--|
| Performance with test batteries | |
| Serial test family | |
| Return times | |
| Other test quantities | |
| Transformation methods: sensitivity | |



Checklist: Practical Aspects

C) Practical Aspects

| | |
|--|--|
| C) Practical Aspects | |
| Tables of parameters available? | |
| Portable implementations available? | |
| Parallelization techniques applicable? | |
| Large samples available? | |
| Efficiency? | |
| Cryptography: security aspects? | |



RNGs: Simulation vs. Cryptography

| Simulation | Cryptography |
|------------------------------|--|
| Theoretical Analysis | |
| Period Length | |
| Known (in most cases) | Unknown (in most cases) |
| Structural Properties | |
| Intrinsic structures welcome | Intrinsic structures are to be avoided |



RNGs: Simulation vs. Cryptography

| Simulation | Cryptography |
|------------------------------|--|
| Theoretical Analysis | |
| Period Length | |
| Known (in most cases) | Unknown (in most cases) |
| Structural Properties | |
| Intrinsic structures welcome | Intrinsic structures are to be avoided |
| Statistical Testing | |
| Extensive results | Lack of published test results |
| Batteries of tests | Under development (NIST) |



RNGs: Simulation vs. Cryptography

| | |
|-----------------------------|----------------------|
| Simulation | Cryptography |
| Practical Aspects | |
| RNGs trimmed for efficiency | RNGs in many flavors |



RNGs: Simulation vs. Cryptography

| Simulation | Cryptography |
|---|---|
| Practical Aspects | |
| RNGs trimmed for efficiency | RNGs in many flavors |
| Design Aspects | |
| Prefer linear algorithms (efficiency!) | Require nonlinear algorithms (security!) |



RNGs: Simulation vs. Cryptography

| Simulation | Cryptography |
|--|-----------------------------------|
| RNG Testing | |
| fair adversary: RNG treated as a black box | freestyle: all attacks allowed |
| test tries to find structures in the output stream | same goal |
| not interested in predictability | try to find the secret key |



NIST Test Suite (NTS)

Comments

▶ Question I:

What are the **redundancies** in this test suite?

For example, NST contains various entropy estimators (Maurer's Universal Test, Approximate Entropy of Pincus and Singer, Serial Test). What is the relation between them?



NIST Test Suite (NTS)

Comments

▶ Question I:

What are the **redundancies** in this test suite?

For example, NST contains various entropy estimators (Maurer's Universal Test, Approximate Entropy of Pincus and Singer, Serial Test). What is the relation between them?

▶ Question II

Which NIST tests detect which kind of defect?

The NTS has not been analyzed with respect to a **defective** RNG. Which tests will detect a given defect (and which tests will not)?



Testing Statistical Tests

Question

How universal is Maurer's Universal Test?



Testing Statistical Tests

Question

How universal is Maurer's Universal Test?

Approach

- ▶ Construct bitstream x_0, x_1, \dots
induce correlations at distance κ :

$$\boxed{x_0}, x_1, x_2, \dots, x_{\kappa-1}, \boxed{x_\kappa}, x_{\kappa+1}, \dots$$

- ▶ Does the statistical test at hand detect this error?



Testing Statistical Tests

Question

How universal is Maurer's Universal Test?

Approach

- ▶ Construct bitstream x_0, x_1, \dots
induce correlations at distance κ :

$$\boxed{x_0}, x_1, x_2, \dots, x_{\kappa-1}, \boxed{x_\kappa}, x_{\kappa+1}, \dots$$

- ▶ Does the statistical test at hand detect this error?

Results

See our "Defective Source Analysis"



Defective Source Analysis

Correlations

Choose order $\kappa, \kappa \geq 1$

Choose random bits

$$x_0, x_1, \dots, x_{\kappa-1}$$



Defective Source Analysis

Correlations

Choose order $\kappa, \kappa \geq 1$

Choose random bits

$$x_0, x_1, \dots, x_{\kappa-1}$$

Choose bias λ

$$x_i = \begin{cases} x_{i-\kappa} & \text{with probability } \lambda \\ 1 - x_{i-\kappa} & \text{with probability } 1 - \lambda \end{cases}$$



Defective Source Analysis

Correlations

Choose order $\kappa, \kappa \geq 1$

Choose random bits

$$x_0, x_1, \dots, x_{\kappa-1}$$

Choose bias λ

$$x_i = \begin{cases} x_{i-\kappa} & \text{with probability } \lambda \\ 1 - x_{i-\kappa} & \text{with probability } 1 - \lambda \end{cases}$$

Choose source probability distribution

$\lambda = 0.5$... i.i.d. uniform

$\lambda \neq 0.5$... i.d. uniform



Defective Source Analysis

▶ Test input x_0, x_1, \dots, x_{m-1} (m bits)



Defective Source Analysis

- ▶ Test input x_0, x_1, \dots, x_{m-1} (m bits)
- ▶ Sample size $n > 1$



Defective Source Analysis

- ▶ Test input x_0, x_1, \dots, x_{m-1} (m bits)
- ▶ Sample size $n > 1$
- ▶ Dimension $d \geq 1$



Defective Source Analysis

- ▶ Test input x_0, x_1, \dots, x_{m-1} (m bits)
- ▶ Sample size $n > 1$
- ▶ Dimension $d \geq 1$
- ▶ Overlapping and non-overlapping d -tuples

$$\tilde{x}_i^d = (x_i, x_{i+1}, \dots, x_{i+d-1})$$

$$\bar{x}_i^d = (x_{i \cdot d}, x_{i \cdot d + 1}, \dots, x_{i \cdot d + d - 1})$$



Defective Source Analysis

- ▶ Test input x_0, x_1, \dots, x_{m-1} (m bits)
- ▶ Sample size $n > 1$
- ▶ Dimension $d \geq 1$
- ▶ Overlapping and non-overlapping d -tuples

$$\tilde{x}_i^d = (x_i, x_{i+1}, \dots, x_{i+d-1})$$

$$\bar{x}_i^d = (x_{i \cdot d}, x_{i \cdot d + 1}, \dots, x_{i \cdot d + d - 1})$$

- ▶ Frequency count

$$\mathbf{a} = (a_1, \dots, a_d) \in \{0, 1\}^d$$

$$\tilde{\pi}_{\mathbf{a}}^d = \frac{1}{n} \#\{0 \leq i < n : \tilde{x}_i = \mathbf{a}\}$$

$$(\bar{\pi}_{\mathbf{a}}^d = \frac{1}{n} \#\{0 \leq i < n : \bar{x}_i = \mathbf{a}\})$$



Defective Source Analysis

Approximate Entropy

$$\hat{H}_f^d = - \sum_{\mathbf{a} \in \mathcal{A}^d} \tilde{\pi}_{\mathbf{a}}^d \log \tilde{\pi}_{\mathbf{a}}^d + \sum_{\mathbf{a} \in \mathcal{A}^{d-1}} \tilde{\pi}_{\mathbf{a}}^{d-1} \log \tilde{\pi}_{\mathbf{a}}^{d-1},$$

$$\hat{I}^d = 2n(1 - \hat{H}_f^d) \xrightarrow{D} \chi_{2^d - 2^{d-1}}^2$$

... (Pincus and Singer, 1998)



Defective Source Analysis

Approximate Entropy

$$\hat{H}_f^d = - \sum_{\mathbf{a} \in \mathcal{A}^d} \tilde{\pi}_{\mathbf{a}}^d \log \tilde{\pi}_{\mathbf{a}}^d + \sum_{\mathbf{a} \in \mathcal{A}^{d-1}} \tilde{\pi}_{\mathbf{a}}^{d-1} \log \tilde{\pi}_{\mathbf{a}}^{d-1},$$

$$\hat{I}^d = 2n(1 - \hat{H}_f^d) \xrightarrow{D} \chi_{2^d - 2^{d-1}}^2$$

... (Pincus and Singer, 1998)

Universal Test

$$\hat{H}_r^d = \frac{1}{d \cdot n} \sum_{i=Q}^{Q+n-1} \log T(i)$$

$$\hat{N}^d = \frac{\hat{H}_r^d - E[\cdot]}{\sqrt{V[\cdot]}} \xrightarrow{D} N[0, 1]$$

... (Maurer, 1992)

($T(i)$: return time for \bar{x}_i^d)



Defective Source Analysis

Overlapping Serial Test

$$\hat{\chi}^d = n \sum_{\mathbf{a} \in \mathcal{A}^d} \frac{(\tilde{\pi}_{\mathbf{a}}^d - (1/2)^d)^2}{(1/2)^d} - n \sum_{\mathbf{a} \in \mathcal{A}^{d-1}} \frac{(\tilde{\pi}_{\mathbf{a}}^{d-1} - (1/2)^{d-1})^2}{(1/2)^{d-1}}$$

... (I.J. Good, 1953)



Defective Source Analysis

Overlapping Serial Test

$$\hat{\chi}^d = n \sum_{\mathbf{a} \in \mathcal{A}^d} \frac{(\tilde{\pi}_{\mathbf{a}}^d - (1/2)^d)^2}{(1/2)^d} - n \sum_{\mathbf{a} \in \mathcal{A}^{d-1}} \frac{(\tilde{\pi}_{\mathbf{a}}^{d-1} - (1/2)^{d-1})^2}{(1/2)^{d-1}}$$

... (I.J. Good, 1953)

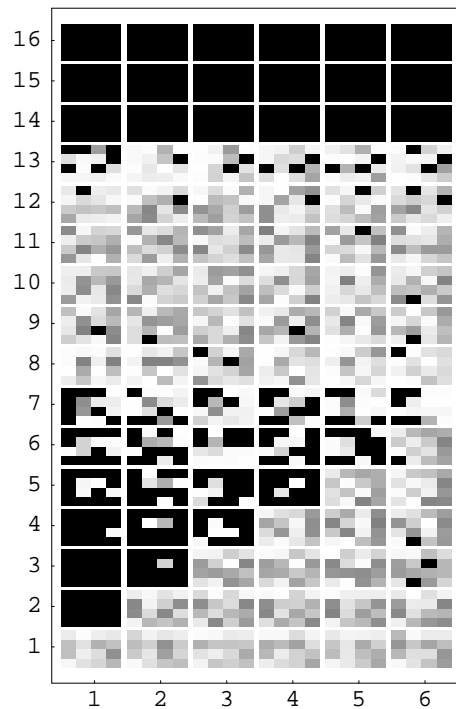
Test Parameters

| | |
|--------------------|---------------------------|
| Sample size | $n = 2^{16}, 2^{18}$ bits |
| No. of repetitions | 16 indept. samples |
| Dimension | $d = 1..16$ |
| Order | $\kappa = 1..6$ |
| Bias λ | $\lambda = 0.49$ |
| Entropy of source | $H \approx 0.999711$ |

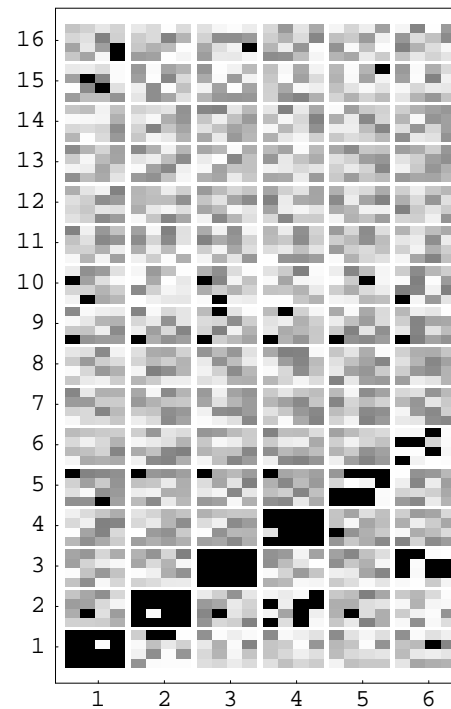
Defective Source Analysis

Results for $n = 2^{16}$ bits

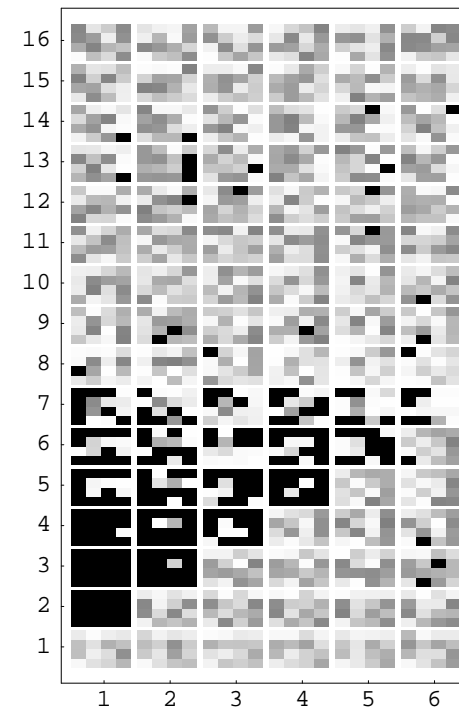
Black dots denote p -values smaller than 0.01.



\hat{I}^d , ApEn



\hat{N}^d , Universal Test

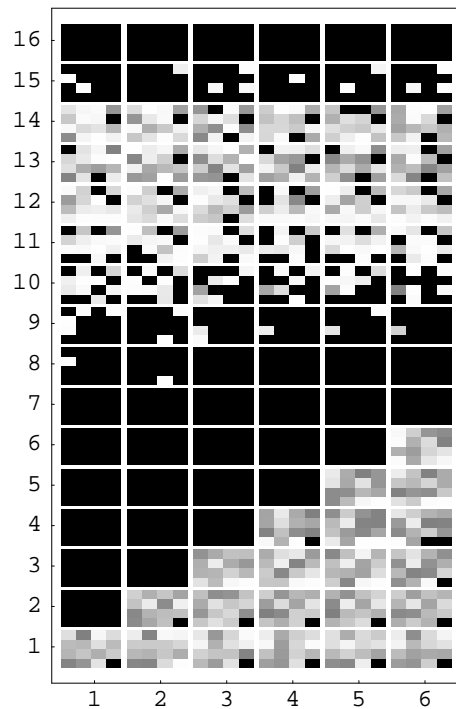


$\hat{\chi}^d$, Overl. Serial T.

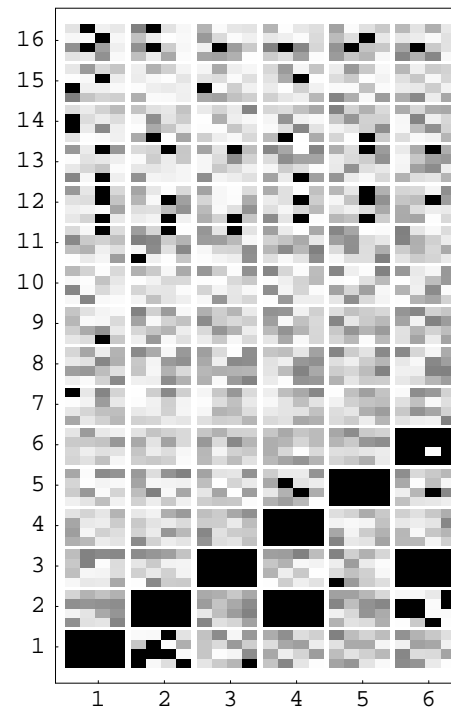
Defective Source Analysis

Results for $n = 2^{18}$ bits

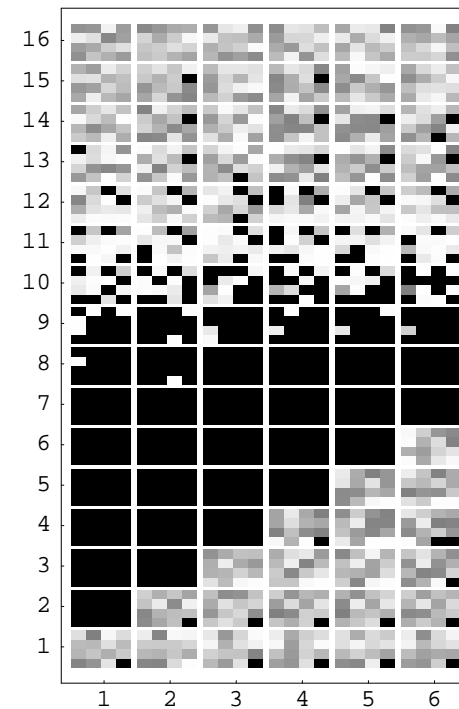
Black dots denote p -values smaller than 0.01.



κ
 \hat{I}^d , ApEn



κ
 \hat{N}^d , Universal Test



κ
 $\hat{\chi}^d$, Overl. Serial T.



AES: Modes of Operation

Output Feedback Mode MODE (OFB)

choose k ... key

choose z_0 ... initial value

compute $(e_k^{(i)}(z_0))_{i \geq 0}$... output stream

$$\underbrace{e_k^{(i)} = e_k \circ \dots \circ e_k}_{i \text{ times}}$$



AES: Modes of Operation

Output Feedback Mode MODE (OFB)

choose k ... key

choose z_0 ... initial value

compute $\left(e_k^{(i)}(z_0) \right)_{i \geq 0}$... output stream

$$e_k^{(i)} = \underbrace{e_k \circ \dots \circ e_k}_{i \text{ times}}$$

PRNG Mode

extract k ... key

choose z_0 ... initial value

compute $\left(e_k^{(i)}(z_0) \right)_{i \geq 0}$... output stream



AES: Modes of Operation

Output Feedback Mode MODE (OFB)

choose k ... key

choose z_0 ... initial value

compute $(e_k^{(i)}(z_0))_{i \geq 0}$... output stream

$$e_k^{(i)} = \underbrace{e_k \circ \dots \circ e_k}_{i \text{ times}}$$

PRNG Mode

extract k ... key

choose z_0 ... initial value

compute $(e_k^{(i)}(z_0))_{i \geq 0}$... output stream

COUNTER MODE

choose k ... key

compute x_0, x_1, \dots (counter) ... plaintext

compute $(e_k(x_i))_{i \geq 0}$... output stream



AES: Setups

Setup 1 – PRNG

k, z_0

$(e_k^{(i)}(z_0))_{i \geq 0}$

... various cases (all-zero, random, ...)

... output stream



AES: Setups

Setup 1 – PRNG

k, z_0

... various cases (all-zero, random, ...)

$(e_k^{(i)}(z_0))_{i \geq 0}$

... output stream

Setup 2 – DIFF

k

... various cases (all-zero, random, ...)

$(p_i)_{i \geq 0}$

... highly patterned plaintext blocks

$(e_k(p_i))_{i \geq 0}$

... output stream



AES: Setups

Setup 1 – PRNG

k, z_0

... various cases (all-zero, random, ...)

$(e_k^{(i)}(z_0))_{i \geq 0}$

... output stream

Setup 2 – DIFF

k

... various cases (all-zero, random, ...)

$(p_i)_{i \geq 0}$

... highly patterned plaintext blocks

$(e_k(p_i))_{i \geq 0}$

... output stream

Setup 3 – PCOUNT

k

... various cases (all-zero, random, ...)

$(p_i)_{i \geq 0}$

... increasing counter

$(e_k(p_i))_{i \geq 0}$

... output stream



AES: Setups

Setup 1 – PRNG

k, z_0

... various cases (all-zero, random, ...)

$(e_k^{(i)}(z_0))_{i \geq 0}$

... output stream

Setup 2 – DIFF

k

... various cases (all-zero, random, ...)

$(p_i)_{i \geq 0}$

... highly patterned plaintext blocks

$(e_k(p_i))_{i \geq 0}$

... output stream

Setup 3 – PCOUNT

k

... various cases (all-zero, random, ...)

$(p_i)_{i \geq 0}$

... increasing counter

$(e_k(p_i))_{i \geq 0}$

... output stream

Setup 4 – KCOUNT

p_0

... plaintext block

$(k_i)_{i \geq 0}$

... incrementing counter

$(e_{k_i}(p_0))_{i \geq 0}$

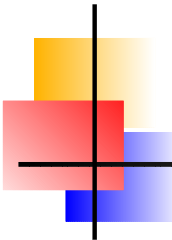
... output stream



AES: Test 1

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES



AES: Test 1

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ cut out every 8th bit, i.e. take y_0, y_8, \dots ;
this yields the bit stream

$$(x_i)_{i \geq 0} \quad (x_i = y_{8i}, i \geq 0)$$



AES: Test 1

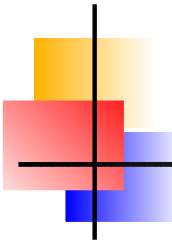
Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ cut out every 8th bit, i.e. take y_0, y_8, \dots ;
this yields the bit stream

$$(x_i)_{i \geq 0} \quad (x_i = y_{8i}, i \geq 0)$$

- ▶ for each combination of dimension d and sample size n , compute

$$\hat{\chi}_1^d(n), \hat{\chi}_2^d(n), \dots, \hat{\chi}_{16}^d(n)$$



AES: Test I

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ cut out every 8th bit, i.e. take y_0, y_8, \dots ;
this yields the bit stream

$$(x_i)_{i \geq 0} \quad (x_i = y_{8i}, i \geq 0)$$

- ▶ for each combination of dimension d and sample size n , compute

$$\hat{\chi}_1^d(n), \hat{\chi}_2^d(n), \dots, \hat{\chi}_{16}^d(n)$$

- ▶ Goodness-of-fit test (KS-Test)



AES: Test I

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ cut out every 8th bit, i.e. take y_0, y_8, \dots ;
this yields the bit stream

$$(x_i)_{i \geq 0} \quad (x_i = y_{8i}, i \geq 0)$$

- ▶ for each combination of dimension d and sample size n , compute

$$\hat{\chi}_1^d(n), \hat{\chi}_2^d(n), \dots, \hat{\chi}_{16}^d(n)$$

- ▶ Goodness-of-fit test (KS-Test)

Test Parameters

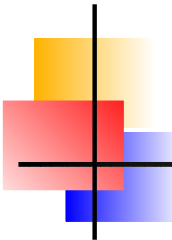
| | |
|--------------------|--|
| Sample size | $n = 2^{18}, 2^{19}, \dots, 2^{28}$ bits |
| No. of repetitions | 16 indept. samples |
| Dimension | $d = 1, 2, 4, 8, 16$ |



AES: Test II

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES

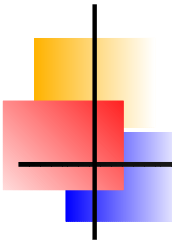


AES: Test II

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ produce d -dimensional overlapping d -tuples

$$\tilde{y}_i^d = (y_i, y_{i+1}, \dots, y_{i+d-1})$$



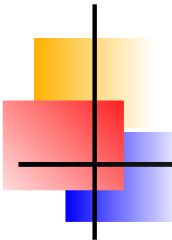
AES: Test II

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ produce d -dimensional overlapping d -tuples

$$\tilde{y}_i^d = (y_i, y_{i+1}, \dots, y_{i+d-1})$$

- ▶ (Dimension reduction) map each d -tuple to one of the three states $-1, 0, 1$



AES: Test II

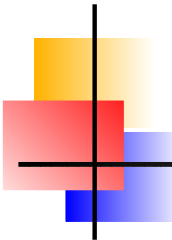
Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ produce d -dimensional overlapping d -tuples

$$\tilde{y}_i^d = (y_i, y_{i+1}, \dots, y_{i+d-1})$$

- ▶ (Dimension reduction) map each d -tuple to one of the three states -1, 0, 1
- ▶ for each combination of the dimension d and the sample size n , compute

$$\hat{\chi}_1^d(n), \hat{\chi}_2^d(n), \dots, \hat{\chi}_{16}^d(n)$$



AES: Test II

Setup

- ▶ consider output bit stream $(y_i)_{i \geq 0}$ of AES
- ▶ produce d -dimensional overlapping d -tuples

$$\tilde{y}_i^d = (y_i, y_{i+1}, \dots, y_{i+d-1})$$

- ▶ (Dimension reduction) map each d -tuple to one of the three states -1, 0, 1
- ▶ for each combination of the dimension d and the sample size n , compute

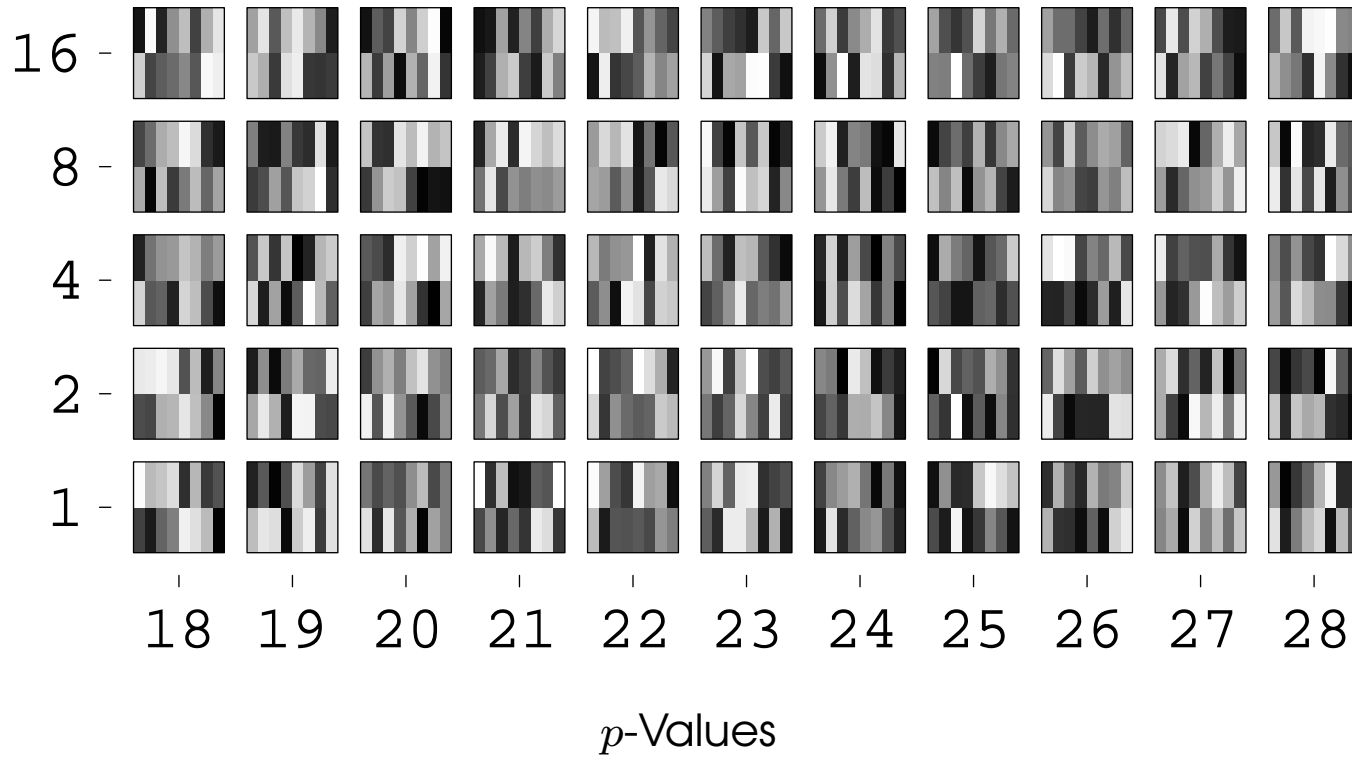
$$\hat{\chi}_1^d(n), \hat{\chi}_2^d(n), \dots, \hat{\chi}_{16}^d(n)$$

- ▶ Goodness-of-fit test (KS-Test)

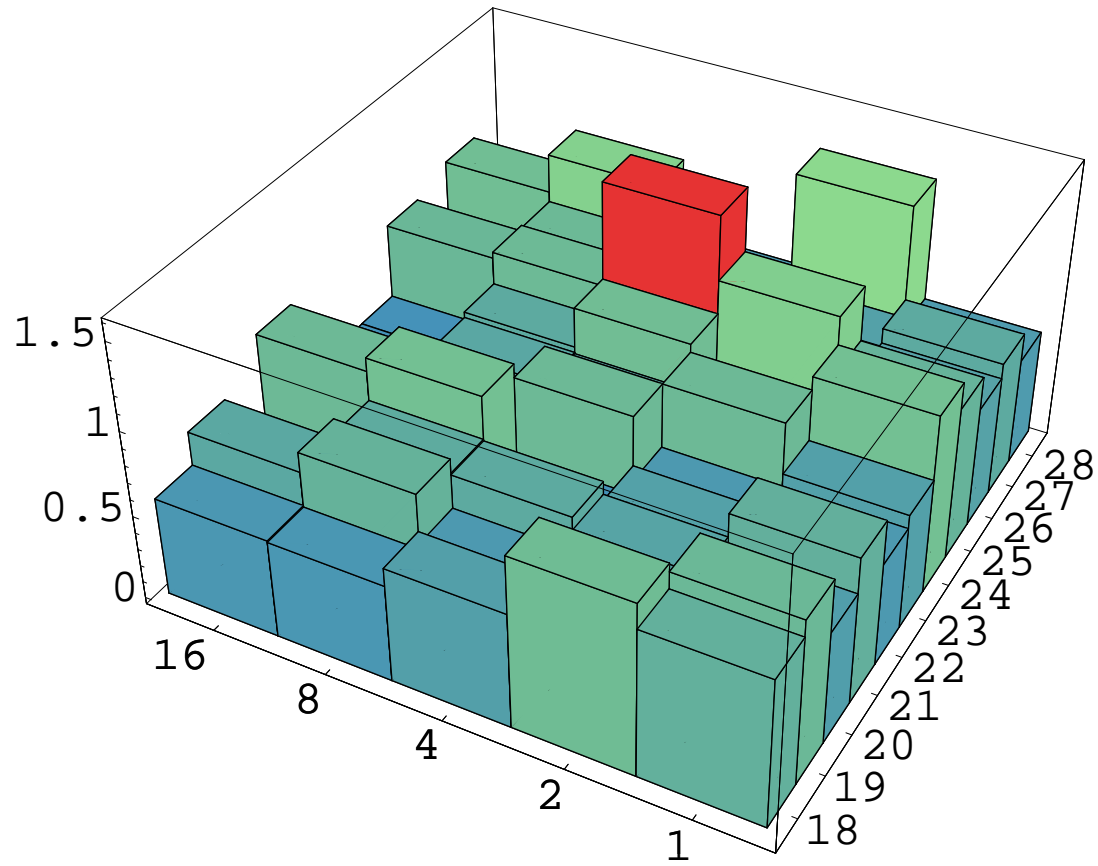
Test Parameters

| | |
|--------------------|--|
| Sample size | $n = 2^{22}, 2^{23}, \dots, 2^{28}$ bits |
| No. of repetitions | 16 indept. samples |
| Dimension | $d = 32, 64, 128, 256$ |

AES: Results of Test I



AES: Results of Test I



KS-Test Values



HAVEG and HAVEGE

HArdware **V**olatile **E**ntropy **G**athering and **E**xpansion
Sendrier and Seznec (INRIA, 2002)

- ▶ Uses processor interrupts to gather entropy



HAVEG and HAVEGE

HArdware **V**olatile **E**ntropy **G**athering and **E**xpansion
Sendrier and Seznec (INRIA, 2002)

- ▶ Uses processor interrupts to gather entropy
- ▶ HAVEG is a passive entropy harvester



HAVEG and HAVEGE

HArdware **V**olatile **E**ntropy **G**athering and **E**xpansion
Sendrier and Seznec (INRIA, 2002)

- ▶ Uses processor interrupts to gather entropy
- ▶ HAVEG is a passive entropy harvester
- ▶ HAVEGE is active, acts on the processor



HAVEG and HAVEGE

Hardware **V**olatile **E**ntropy **G**athering and **E**xpansion
Sendrier and Seznec (INRIA, 2002)

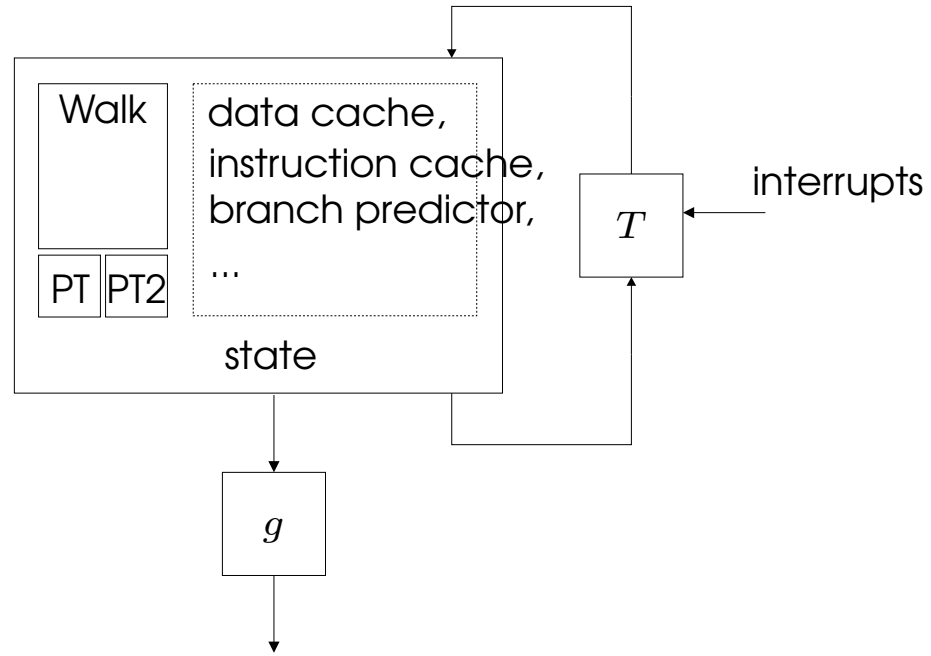
- ▶ Uses processor interrupts to gather entropy
- ▶ HAVEG is a passive entropy harvester
- ▶ HAVEGE is active, acts on the processor

The idea behind

Each attempt to read the inner state of the processor **alters** it at the same time.

Complete state of HAVEGE cannot be observed without freezing the clock of the processor.

Structure of HAVEGE



The General Structure of HAVEGE



RNGs: State of the Art

Present Situation

Like in the race between cryptographers and cryptanalysts, presently the designers of RNGs are winning against the designers of statistical tests.

The intrinsic structures of modern RNGs, in particular of good cryptographic RNGs, are **too complicated to be detected** by current statistical tests.

Future developments

New ideas for testing are needed. This will take some time.